

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	11807	(light\$4 or illuminat\$4 or lamp\$1)and(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1)and inspect\$3 and components and(axial\$3 or horizontal\$3)and(off adj axial\$4 or off-axis or vertical\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/11 12:14
L2	7891	L1 and (edge\$1 or contour\$1 or boundar\$3 or border\$1 or gradient or filter\$3)and (compari\$4 or match\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/11 11:53
L3	447	L2 and (locat\$4 or determin\$4 or find\$3)near feature\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/11 11:55
L4	28	L3 and(dual adj light or twine or two adj light)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/11 12:09
L5	5	L3 and(dual adj light or twine or two adj light)same(simultaneously or together or concurrently)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/11 12:13
L6	5	L5 and analys\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/11 12:15
L7	0	L6 and analys\$3 near3 components	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/11 12:15

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	7003	(light\$4 or illuminat\$4 or lamp\$1)and(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1)and inspect\$3 and components and(axial\$3 or horizontal\$3)and(off adj axial\$4 or off-axis or vertical\$4)	USPAT	OR	ON	2005/11/11 14:23
L2	4	L1 and(edge\$1 or contour\$1 or boundar\$3 or border\$1 or gradient or filter\$3)and (compari\$4 or match\$3)and (locat\$4 or determin\$4 or find\$3)near feature\$1 and(dual adj light or twine or two adj light)same(simultaneously or together or concurrently)and analys\$3	USPAT	OR	ON	2005/11/11 14:29
L3	2948	382/141,145,147,149,199,266,294.ccls.	USPAT	OR	ON	2005/11/11 14:25
L4	505	250/559.05,559.16,559.22,559.11.ccls.	USPAT	OR	ON	2005/11/11 14:26
L5	634	348/87,92,126.ccls.	USPAT	OR	ON	2005/11/11 14:26
L6	194	L1 and L3	USPAT	OR	ON	2005/11/11 14:27
L7	0	L6 and(edge\$1 or contour\$1 or boundar\$3 or border\$1 or gradient or filter\$3)and (compari\$4 or match\$3)and (locat\$4 or determin\$4 or find\$3)near feature\$1 and(dual adj light or twine or two adj light)same(simultaneously or together or concurrently)and analys\$3	USPAT	OR	ON	2005/11/11 14:27
L8	30	L1 and L4	USPAT	OR	ON	2005/11/11 14:28
L9	0	L8 and(edge\$1 or contour\$1 or boundar\$3 or border\$1 or gradient or filter\$3)and (compari\$4 or match\$3)and (locat\$4 or determin\$4 or find\$3)near feature\$1 and(dual adj light or twine or two adj light)same(simultaneously or together or concurrently)and analys\$3	USPAT	OR	ON	2005/11/11 14:28
L10	82	L1 and L5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/11 14:28

L11	0	L10 and(edge\$1 or contour\$1 or boundar\$3 or border\$1 or gradient or filter\$3)and (compari\$4 or match\$3)and (locat\$4 or determin\$4 or find\$3)near feature\$1 and(dual adj light or twine or two adj light)same(simultaneously or together or concurrently).	USPAT	OR	ON	2005/11/11 14:29
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Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	736	(light\$4 or illuminat\$4 or lamp\$1)and(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1)and inspect\$3 and components and(axial\$3 or horizontal\$3)and(off adj axial\$4 or off-axis or vertical\$4).CLM.	US-PGPUB	OR	ON	2005/11/11 14:38
L2	297	L1 and(edge\$1 or contour\$1 or boundar\$3 or border\$1 or gradient or filter\$3)and(compar\$5 or match\$3)and(locat\$4 or determin\$4 or find\$3)and feature\$1 and(dual adj light or twine or two adj light or "2")and(simultaneously or together or concurrently)and analys\$3	US-PGPUB	OR	ON	2005/11/11 14:41
L3	296863	L2 and (light\$4 or illuminat\$4 or lamp\$1)and components generat\$3 and (acceptance or reject\$3 or pass or fail or fault or flaw)	US-PGPUB	OR	ON	2005/11/11 14:40
L4	297	L1 and L2 and L3	US-PGPUB	OR	ON	2005/11/11 14:40
L5	296	L4 and(edge\$1 or contour\$1 or boundar\$3 or border\$1 or gradient or filter\$3)and(compar\$5 or match\$3)and first and second	US-PGPUB	OR	ON	2005/11/11 14:42
L6	0	L4 and(edge\$1 or contour\$1 or boundar\$3 or border\$1 or gradient or filter\$3)and(compar\$5 or match\$3)and(first near3 gradient and second near3 gradient)	US-PGPUB	OR	ON	2005/11/11 14:43

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1	INZZ	(light* OR illuminat* OR lamp*) AND (wafer* OR semiconductor* OR chip* OR substrat*) AND inspect* AND components AND (axial* OR horizontal*) AND (off ADJ axial* OR off-axis OR vertical*)	unrestricted	0	-
2	INZZ	inspect* AND components AND (edge* OR contour* OR ADJ boundar* OR border* OR gradient OR filter*) AND (compar* OR match*) AND (locat* OR determin* OR find*) AND feature* AND (dual ADJ light OR twine OR two ADJ light OR '2') AND (simultaneously OR together OR concurrently)	unrestricted	0	-

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